

ENBIS-23 Valencia Conference

Tuesday, 12 September 2023

CONTRIBUTED Industry 2 - 2.13 (16:40 - 17:40)

-Conveners: András Zempléni

time	[id] title	presenter
16:40	[154] Dynamic Bayesian Network-Based Run-to-Run Control Scheme for Optimal Quality Engineering in Semiconductor Manufacturing	YANG, Wei-Ting
17:00	[24] Multivariate Bayesian Mixed Model for Method Comparability	TUMOLVA, Olympia
17:20	[81] Process Optimization Using Bayesian Models for Bounded Data	ENSOY-MUSORO, Chellafe